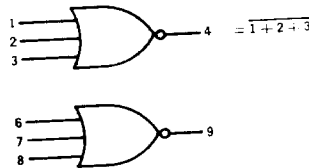
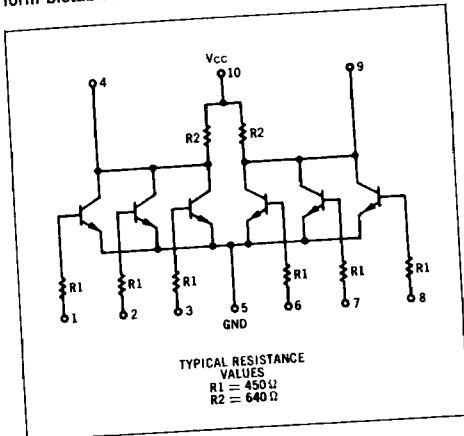


DUAL3-INPUT GATES

MC915 • MC815

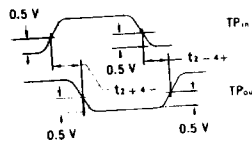
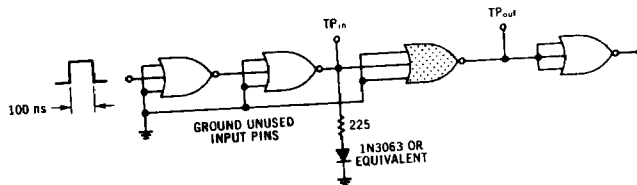
Available in TO-100 Metal Can, Add "G" Suffix.
 Available in TO-91 Flat Package, Add "F" Suffix.

Two 3-input positive logic NOR gates in a single package may be used independently, paralleled for increasing the number of inputs (subject to loading rules), or cross-connected to form bistable elements.



"F" PACKAGE AND "G" PACKAGE
 PIN-OUTS ARE THE SAME

SWITCHING TIMES TEST CIRCUIT AND WAVEFORMS



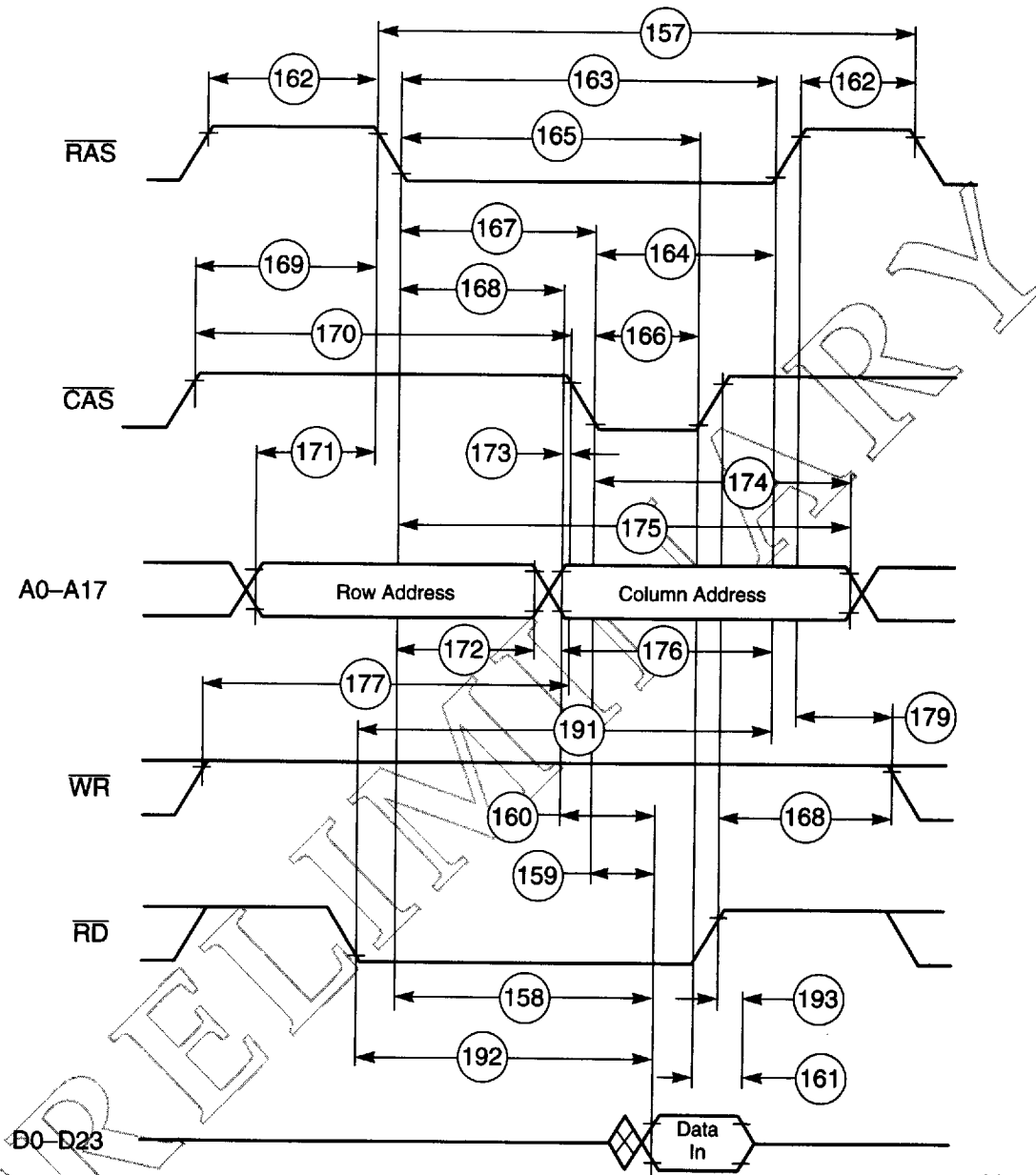
ELECTRICAL CHARACTERISTICS

Test procedures are shown for one gate only.
Other gates are tested in the same manner.

Characteristic	Symbol	Pin Under Test	TEST VOLTAGE VALUES													
			@ Test Temperature						TEST VOLTAGE VALUES (Volts)							
			-55°C		+25°C		+100°C		V _{in}	V _{on}	V _{bot}	V _{off}	V _{CC}	Grnd		
Input Current	I _{In}	1 2 3	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max
Output Current	I _{A5}	4	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max
Output Leakage Current	I _{CEX}	4	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max
Output Voltage	V _{out}	4	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max
Saturation Voltage	V _{CE(sat)}	4	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max
Switching Time	t	2+4- 2+4-	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max

Ground inputs of gate not under test. Other pins not listed are left open.

33



AA0476

Figure 2-18 DRAM Out-of-Page Read Access

Preliminary Data